

Scanning Electron Microscopy and X-ray Microanalysis, 10.0 credits

Svepelektronmikroskopi och röntgenmikroanalys, 10.0 hp

Third-cycle education course

6FIEI45

Department of Management and Engineering

Valid from: Second half-year 2023

Approved by
Head of Department

Approved
2022-10-07

Revised by
Head of Department

Revised
2023-11-13

Registration number
IEI-2023-00616

Grading

Two-grade scale